Supporting Information



Figure S1[†] Distribution of Ru oxidation state for various binary Ru-Ti oxides, Ru metal and RuO₂ are used as reference samples.



Figure S2[†] Fitting results of (a) Ru and (b) Ti K-edge EXAFS spectra for the standard RuO₂, rutile

TiO₂ and various binary Ru-Ti oxides.



Figure S3[†] HR-TEM morphologies and the corresponding electron diffraction patterns for (a-c) RuTi-200 and (d-f) RuTi-300. The clear lattice fringe and diffraction point of RuTi-H300 indicates an increased crystallinity characteristic and the formation of long-range order structure.



Figure S4[†] HR-TEM image measured at the high angle annular dark field (HAADF) mode and the corresponding EDS mapping results of RuTi-300. The red and yellow spots shown in the mapping profile stand for Ru and Ti elements, respectively. It can be clearly seen that a small amount of Ti element exists inside the RuO₂ nanorods. The calculated Ru/Ti atomic ratio is approximately 96.2/3.8 (The intensity of Ti is lower than that of Ru).



Figure S5[†] TEM morphologies for (a) Ru-as, (b) Ru-150, (c) Ru-200, (d) Ru-250, (e) Ru-300, and (f)

Ru-300 samples.



Figure S6[†] Electrochemical impedance spectra of (a) RuO₂ and (b) RuTiO₂ nanocomposites annealed at various temperatures. EIS results were measured at 0.5 V in 0.5 M H₂SO₄. Inset shows the spectra in the high-frequency region.



Figure S7[†] Frequency dependence of specific capacitance for RuO_2 and $(Ru-Ti)O_2$ electrode annealed at various temperatures (0.5±0.02 mg cm⁻²). The results were measured at 0.5 V and the electrolyte for the electrochemical measurements is 0.5 M H₂SO₄.